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Application/Control No.	Applicant(s)/Patent und Reexamination	er
10/725,722	KANG ET AL.	
Examiner	Art Unit	
Mila Airapetian	3625	

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Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
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Keyterm search on EAST (see attached)	6/8/2006	MA